



ITW2N7002

N-Channel 60V(D-S) MOSFET

GENERAL DESCRIPTION

The ITW2N7002 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

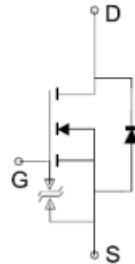
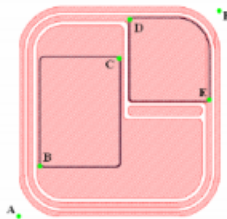
FEATURES

- $R_{DS(ON)} \leq 3\Omega @ V_{GS}=10V$
 - $R_{DS(ON)} \leq 4\Omega @ V_{GS}=4.5V$
 - ESD Protection
 - Super high density cell design for extremely low $R_{DS(ON)}$
 - Exceptional on-resistance and maximum DC current capability
 - Capable doing Cu wire bonding
- #### APPLICATIONS
- Power Management in Note book
 - Portable Equipment
 - Battery Powered System
 - Load Switch
 - DSC

CHIP APPEARANCE

Die Size: X= 250 μ m (w/o S/L) Gate Pad Size: X = 100 μ m
Y = 250 μ m (w/o S/L) Y = 100 μ m

A : (0 , 0)
B : (25 , 60)
C : (125 , 190)
D : (137 , 237)
E : (237 , 137)
F : (250 , 250)



N-Channel MOSFET

Scribe Line(S/L) : 60 μ m

Chip Size	310 X 310 μ m	Top Metal	Al-Cu
Gate Pad Size	100 X 100 μ m	Top Metal Thickness	3.3 μ m (Typ)
Wafer Size	8 inch	*Back Metal	Ti/Ni/Sn
Chip Thickness	6 mil (Typical)		
Valid Wafer Area	Exclusion zone is 3mm from the wafer edge.		

* Reserved in N2 locker and warranty 2 months after shipping.

Probing: 0.1% sample probed in order to guarantee minimum yield.



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Absolute Maximum Ratings (TA=25°C Unless Otherwise Noted)

Parameter	Symbol	Maximum Ratings	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V

Electrical Characteristics (Tj = 25°C Unless Otherwise Specified)

Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250 \mu A$	60			V
V _{GS(th)}	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250 \mu A$	0.8		2.5	V
I _{GSS}	Gate-Body Leakage	$V_{DS}=0V, V_{GS}=\pm 20V$			± 10	μA
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=48V, V_{GS}=0V$			1	μA
R _{DS(ON)}	Drain-Source On-Resistance*	$V_{GS}=10V, I_D=500mA$			3	Ω
		$V_{GS}=4.5V, I_D=200mA$			4	
V _{SD}	Diode Forward Voltage *	$I_S=500mA, V_{GS}=0V$			1.3	V

Notes: a. Based on Eutectic and bond wire Cu wire 1.0mil x1(S), Cu wire 1.0mil x 1 (G) on each die of small SOT-23 package with Cu lead frame.

b. Pulse test; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.